Search Notes

Application/Control No	Applicant(s)/Patent unde Reexamination	er
09/841,598	MATSUDA, KOUICHI	
Examiner	Art Unit	
Sargon N. Nano	2157	

SEARCHED				
Class	Subclass	Date	Examiner	
709	203-204 206 223-224 227-228	5/3/2005	SN	
		_		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
709	204 206	5/3/2005	SN	
709	224 227	5/3/2005	SN	

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East Search (see attached search report)	5/3/2005	SN
Consulted with primary Examiner Saleh Najjar A.U. 2157	5/3/2005	SN
Npl Search (google search, IEEE search)	5/3/2005	SN
<del></del>		